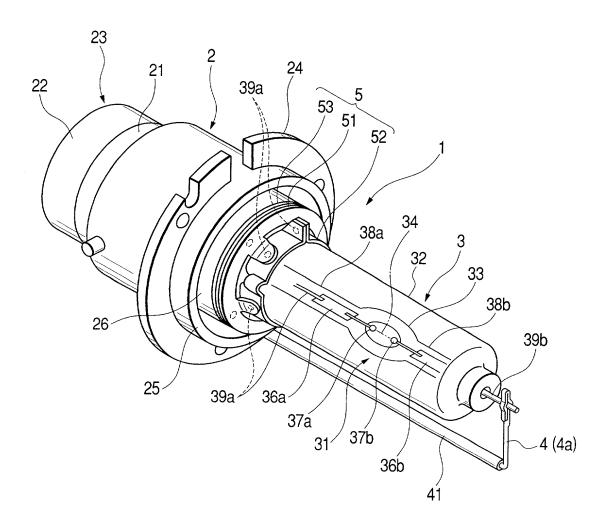
TSUDA et al.
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FIG. 1



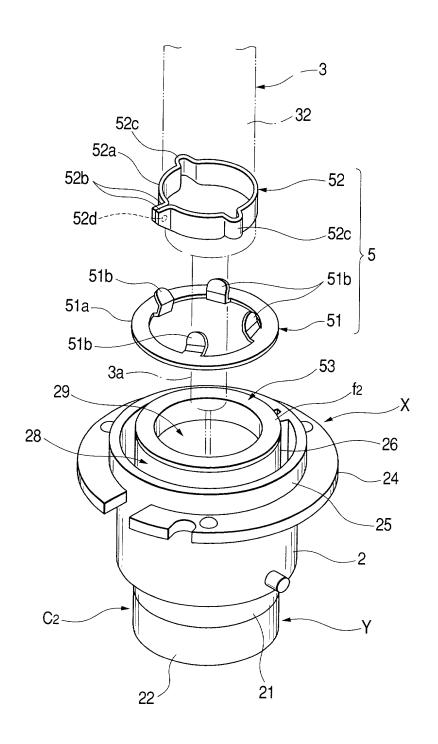
TSUDA et al.
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85-35 ب ج ~ (%) 52 -51c -51b 51a Ŋ 51c 51 23 8 ဖ် 6 2 -23 Ω ප

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FIG. 3



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FIG. 4

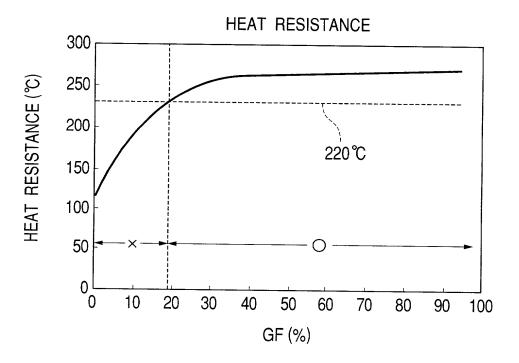
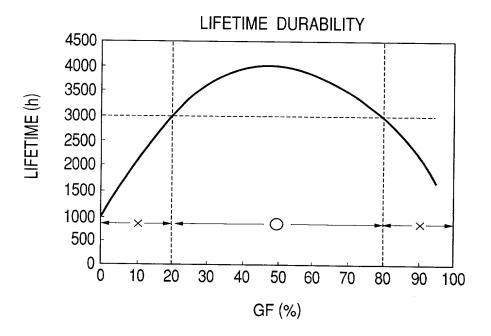


FIG. 5



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FIG. 6

CONNECTOR FITTING STRENGTH

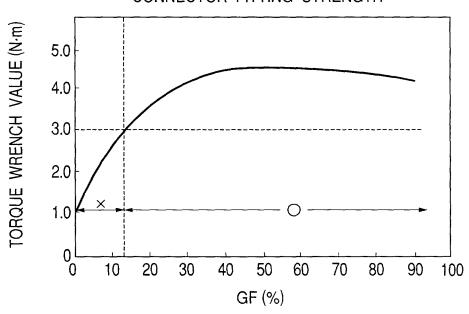


FIG. 7

DIMENSIONAL ACCURACY OF BASE PORTION 1.80 DIMENSIONAL PROCESS CAPABILITY CPK 1.60 1.40 1.20 1.00 0.80 0.60 0.40 0.20 0.00 70 10 20 40 50 60 80 90 30 100 GF (%)

FIG. 8

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06	NO ABNOR- MALITY	2174 (WELD CRACK)	0.45	17.1
80	NO ABNOR- MALITY	3350	4.4	07:1
02	NO ABNOR-MALITY	4680	4.4	8 0
09	NO ABNOR- MALITY	5000≤	4.5	17.1
50	NO ABNOR- MALITY O	5000≤	4.5	1.72 O
40	NO ABNOR- NO ABNOR- NO ABNOR- NO ABNOR- NO ABNOR- NO ABNOR- MALITY MALITY MALITY MALITY O O O O	5000≤	4.4	07.1
30	NO ABNOR- MALITY O	4680	4.2	0.0
70	NO ABNOR- MALITY O	3350	3.5	1.08
15	DEFORMA- TION DEVELOPED ×	2733 (VOID CRACK) ×	3.2	0.89 (LARGE SHRINKAGE) ×
9	DEFORMA- TION DEVELOPED ×	2485 (VOID CRACK) ×	5.6 ×	0.43 (LARGE SHRINKAGE) ×
5	DEFORMA- TION DEVELOPED ×	1786 (VOID CRACK) ×	5. ×	0.22 (LARGE SHRINKAGE) ×
GLASS FIBER RATIO (%)	HEAT RESISTANCE	LIFETIME DURABILITY LIGHTING TIME: 3000h≦	CONNECTOR FITTING STRENGTH TEST 3.0(N·m)≦	PLUG DIMENSIONAL ACCURACY PROCESS CAPABILITY:1.0≦